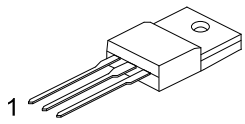
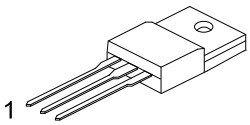
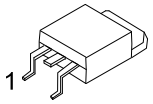
3.0A, 1200V N-CHANNEL SUPER-JUNCTION MOSFET



TO-220F1



TO-220F2



TO-252

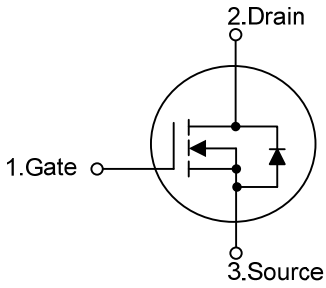
■ DESCRIPTION

The UTC **3NM120-Q** is a Super Junction MOSFET Structure and is designed to have better characteristics, such as fast switching time, low gate charge, low on-state resistance and a high rugged avalanche characteristics. This power MOSFET is usually used at AC-DC converters for power applications.

■ FEATURES

* $R_{DS(ON)} \leq 5.6\ \Omega$ @ V_{GS}=10V, I_D=1.5A
* High Switching Speed

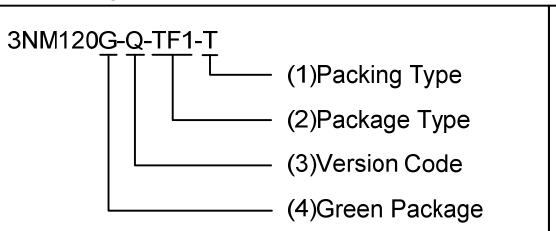
■ SYMBOL



■ ORDERING INFORMATION

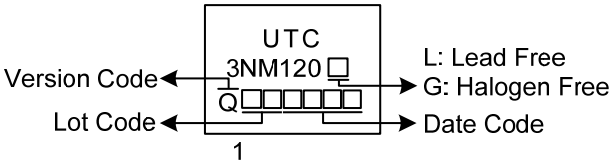
Ordering Number		Package	Pin Assignment			Packing
Lead Free	Halogen Free		1	2	3	
3NM120L-Q-TF1-T	3NM120G-Q-TF1-T	TO-220F1	G	D	S	Tube
3NM120L-Q-TF2-T	3NM120G-Q-TF2-T	TO-220F2	G	D	S	Tube
3NM120L-Q-TN3-R	3NM120G-Q-TN3-R	TO-252	G	D	S	Tape Reel

Note: Pin Assignment: G: Gate D: Drain S: Source



(1) T: Tube, R: Tape Reel
(2) TF1: TO-220F1, TF2: TO-220F2, TN3: TO-252
(3) Version Q
(4) G: Halogen Free and Lead Free, L: Lead Free

■ MARKING



■ ABSOLUTE MAXIMUM RATINGS (unless otherwise specified)

PARAMETER			SYMBOL	RATINGS	UNIT
Drain-Source Voltage			V_{DSS}	1200	V
Gate-Source Voltage			V_{GSS}	±30	V
Continuous Drain Current	Continuous		I_D	3	A
	Pulsed		I_{DM}	6	A
Avalanche Energy	Single Pulsed (Note 3)		E_{AS}	65	mJ
Peak Diode Recovery dv/dt (Note 4)			dv/dt	2	V/ns
Power Dissipation	TO-220F1/TO-220F2		P_D	22	W
	TO-252	Steady State		24	W
		t ≤ 5s		45	W
Junction Temperature			T_J	+150	°C
Storage Temperature			T_{STG}	-55 ~ +150	°C

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.
2. Repetitive Rating: Pulse width limited by maximum junction temperature.
3. L = 100mH, I_{AS} = 1.14A, V_{DD} = 50V, R_G = 25 Ω Starting T_J = 25°C
4. I_{SD} ≤ 3.0A, di/dt ≤ 200A/μs, V_{DD} ≤ BV_{DSS}, Starting T_J = 25°C

■ THERMAL DATA

PARAMETER			SYMBOL	RATING	UNIT
Junction to Ambient	TO-220F1/TO-220F2		θ_{JA}	62.5	°C/W
	TO-252			110	°C/W
Junction to Case	TO-220F1/TO-220F2		θ_{JC}	5.68	°C/W
	TO-252	Steady State		5.2 (Note)	°C/W
		t ≤ 5s		2.77 (Note)	°C/W

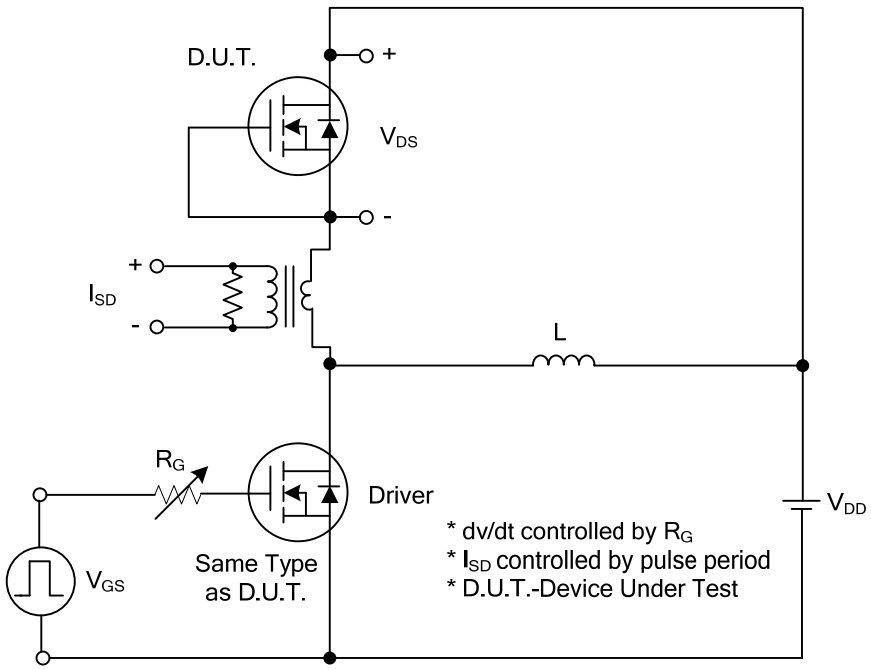
Note: Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate.

■ ELECTRICAL CHARACTERISTICS

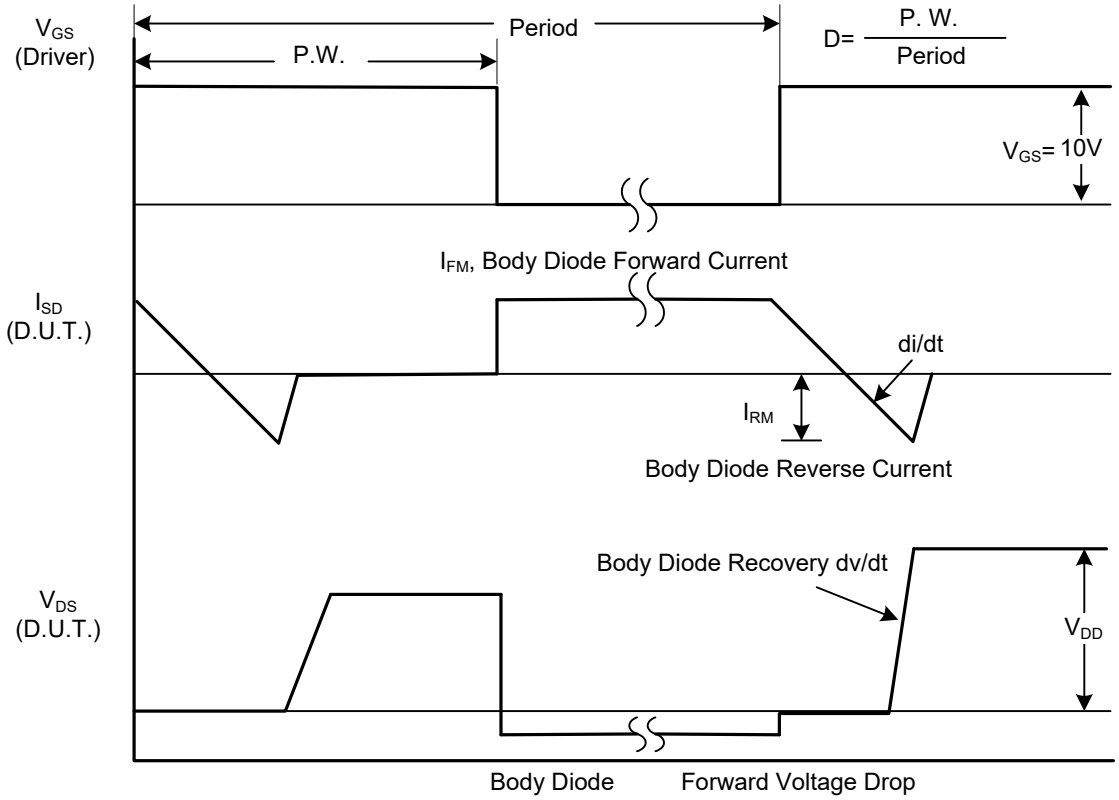
PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage		BV_{DSS}	I_D=250μA, V_{GS}=0V	1200			V
Drain-Source Leakage Current		I_{DSS}	V_{DS}=1200V, V_{GS}=0V			10	μA
Gate-Source Leakage Current	Forward	I_{GSS}	V_{GS}=+30V, V_{DS}=0V			+100	nA
	Reverse		V_{GS}=-30V, V_{DS}=0V			-100	nA
ON CHARACTERISTICS							
Gate Threshold Voltage		$V_{GS(TH)}$	V_{DS}=V_{GS}, I_D=250μA	2.5		4.5	V
Static Drain-Source On-State Resistance		$R_{DS(ON)}$	V_{GS}=10V, I_D=1.5A			5.6	Ω
DYNAMIC PARAMETERS							
Input Capacitance		C_{ISS}	V_{GS}=0V, V_{DS}=50V, f=1.0MHz		290		pF
Output Capacitance		C_{OSS}			22		pF
Reverse Transfer Capacitance		C_{RSS}			2.3		pF
SWITCHING PARAMETERS							
Total Gate Charge		Q_G	V_{DS}=960V, V_{GS}=10V, I_D=3.0A (Note 1, 2)		18		nC
Gate to Source Charge		Q_{GS}			6		nC
Gate to Drain Charge		Q_{GD}			5		nC
Turn-ON Delay Time		$t_{D(ON)}$	V_{DD}=100V, V_{GS}=10V, I_D=3.0A, R_G=25Ω (Note 1, 2)		6.4		ns
Rise Time		t_R			17		ns
Turn-OFF Delay Time		$t_{D(OFF)}$			38		ns
Fall-Time		t_F			32		ns
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS							
Maximum Body-Diode Continuous Current		I_S				3	A
Maximum Body-Diode Pulsed Current		I_{SM}				6	A
Drain-Source Diode Forward Voltage		V_{SD}	I_S=3.0A, V_{GS}=0V			1.4	V
Body Diode Reverse Recovery Time		t_{rr}	I_S=3.0A, V_{GS}=0V, dI_F/dt=100A/μs (Note 1)		516		ns
Reverse Recovery Charge		Q_{rr}			4.3		μC

Notes: 1. Pulse Test: Pulse width ≤ 1200μs, Duty cycle ≤ 2%.
2. Essentially independent of operating temperature.

■ TEST CIRCUITS AND WAVEFORMS

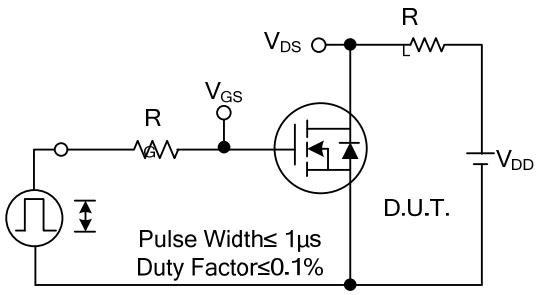


Peak Diode Recovery dv/dt Test Circuit

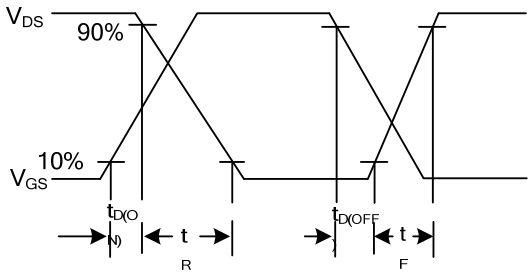


Peak Diode Recovery dv/dt Waveforms

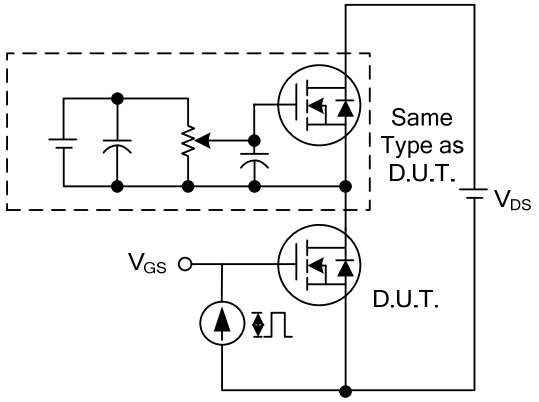
■ TEST CIRCUITS AND WAVEFORMS



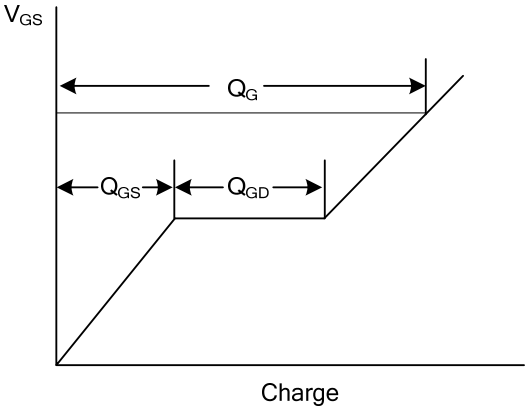
Switching Test Circuit



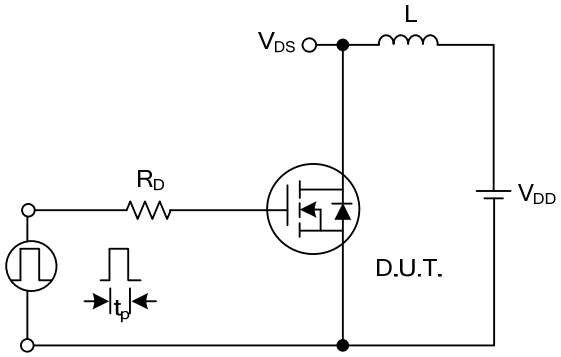
Switching Waveforms



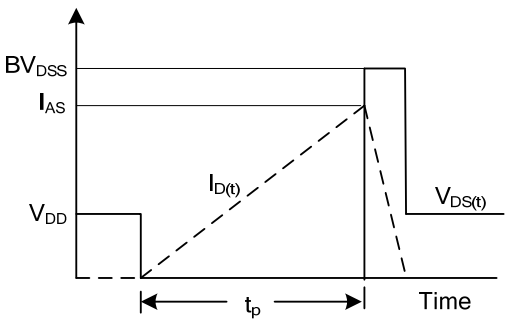
Gate Charge Test Circuit



Gate Charge Waveform



Unclamped Inductive Switching Test Circuit



Unclamped Inductive Switching Waveforms